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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/622,652	07/21/2003	Michael Setton	015290-756	3865
7590 05/19/2005			EXAMINER	
Peter K. Skiff			POMPEY, RON EVERETT	
BURNS, DOANE, SWECKER & MATHIS, L.L.P.				
P.O. Box 1404			ART UNIT	PAPER NUMBER
Alexandria, V	A 22313-1404		2812	

DATE MAILED: 05/19/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

			<u>(4:H</u>			
	Application No.	Applicant(s)	71 .2			
	10/622,652	SETTON, MICHAEL				
Office Action Summary	Examiner	Art Unit				
	Ron E. Pompey	2812				
The MAILING DATE of this communication Period for Reply	appears on the cover sheet with	h the correspondence address				
A SHORTENED STATUTORY PERIOD FOR RE THE MAILING DATE OF THIS COMMUNICATIO - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a - If NO period for reply is specified above, the maximum statutory per - Failure to reply within the set or extended period for reply will, by sta Any reply received by the Office later than three months after the magnined patent term adjustment. See 37 CFR 1.704(b).	N. R 1.136(a). In no event, however, may a reply within the statutory minimum of thirty riod will apply and will expire SIX (6) MONT atute, cause the application to become ABA	ply be timely filed (30) days will be considered timely. HS from the mailing date of this communicati	on.			
Status						
1) Responsive to communication(s) filed on 12	2 April 2005.					
	his action is non-final.					
3) Since this application is in condition for allo	wance except for formal matte	rs, prosecution as to the ments	is			
closed in accordance with the practice unde	er <i>Ex parte Quayle</i> , 1935 C.D.	11, 453 O.G. 213.				
Disposition of Claims						
4)⊠ Claim(s) 22-43 is/are pending in the applica	ation.					
4a) Of the above claim(s) is/are without						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>22-43</u> is/are rejected.						
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and	d/or election requirement.					
Application Papers						
9) The specification is objected to by the Exam	iner.					
	DIX The drawing(s) filed on 7/21/13 is/are: a) X accepted or b) □ objected to by the Examiner.					
Applicant may not request that any objection to t	he drawing(s) be held in abeyanc	e. See 37 CFR 1.85(a).				
Replacement drawing sheet(s) including the corr	rection is required if the drawing(s	i) is objected to. See 37 CFR 1.121	(d).			
11)☐ The oath or declaration is objected to by the	Examiner. Note the attached	Office Action or form PTO-152.				
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for fore a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the p application from the International Bur * See the attached detailed Office action for a light	ents have been received. ents have been received in Ap priority documents have been re reau (PCT Rule 17.2(a)).	pplication No received in this National Stage				
Attachment(s)						
Notice of References Cited (PTO-892)	4) 🔲 Interview Su	mmary (PTO-413)				
2) D Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/	/Mail Date				
 Information Disclosure Statement(s) (PTO-1449 or PTO/SB/Paper No(s)/Mail Date 	08) 5) Notice of Info	ormal Patent Application (PTO-152) 				

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DETAILED ACTION

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Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 22-43 are rejected under 35 U.S.C. 103(a) as being unpatentable over Sanchez (US 5,091,763) and further in view of Wu (5,880,508) and Moslehi (5,322,809).

Sanchez discloses the limitations of:

an interfacial layer (14, fig. 2), on a silicon semiconductor substrate;

a gate electrode (16, fig. 2) of an electrically conductive material, wherein the electrode is formed from a metal that is selected from the group consisting of doped polysilicon, TiN, W, Ta, Mo and multilayer thereof;

a gate electrode having a width of less than 0.3 micron covering the high dielectric constant layer (col.3, lns.34-37);

first (18a, fig. 2) and second (18b, fig. 2) lightly doped regions of a second conductivity type disposed on respective areas of the substrate surface;

source and drain regions (22a-b, fig. 2) that are adjacent the gate electrode; a pair of first non-conductive spacers (24a-b, fig. 2), which comprise an oxide or nitride material, formed adjacent to the gate electrode and on the interfacial layer;

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a pair of second non-conductive spacers (28a-b, fig. 2) that are adjacent to the first spacers and the high dielectric, which also are formed over the lightly doped regions and on the interfacial layer(col. 9, Ins. 35-42); and

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a silicide layer (26, fig. 3) on the source and drain regions (col. 4, In. 13 – col. 6, In. 21).

3. Sanchez does not disclose the claimed limitation(s) of:

a high dielectric constant layer (2, fig. 5a), that comprises a material that is selected from the group consisting of Ta_2O_5 , $Ta2(O_{1-x}N_x)_5$, a solid solution of $(Ta_2O_5)_r - (TiO_2)_{1-r}$, a solid solution of $(Ta_2O_5)_s - (Al_2O_3)_{1-s}$, a solid solution of $(Ta_2O_5)_t - (ZrO_2)_{1-t}$, a solid solution of $(Ta_2O_5)_u - (HfO_2)_{1-u}$, on the interfacial layer; and

an insulator layer covering the device and defining a first contact hole that is filled with a first contact material and a second contact hole that are filled with a second contact material, wherein the insulator layer has a substantially planar surface;

wherein the interfacial layer comprises silicon nitride or silicon oxynitride; and a barrier layer between the gate electrode and the high dielectric constant layer.

However,

a. Wu discloses the above claimed limitations regarding:

a high dielectric constant layer (8, fig. 1), that comprises a material of Ta₂O₅, wherein the interfacial layer (6, fig. 1) comprises silicon nitride or silicon oxynitride; and a barrier layer (10, fig. 2) between the gate electrode and the high dielectric constant layer in column 2, line 63 – column 3, line 20.

Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to combine Sanchez with Wu, because the high dielectric constant layer provides for a gate insulator layer that reduces hot carrier effect and the barrier layer helps to provide better adhesion between the high dielectric constant layer and the gate.

b. Moslehi discloses the above claimed limitations regarding:

wherein the interlayer insulator is planar (46, fig. 3a) and silicide (41, fig. 2i) on the source and drain regions.

Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to combine Moslehi with Sanchez, because Moslehi the silicide on the source and drain provide for a lower resistivty for better electrical conduction for metal contact and the planar insulator keeps topography level so preceding layers can be uniform.

c. Neither Sanchez, Wu nor Moslehi disclose:

the various high dielectric compositions, consisting of $Ta_2(O_{1-x}N_x)_5$ wherein x ranges from greater than 0 to 0.6, a solid solution of $(Ta_2O_5)_{r}$ - $(TiO_2)_{1-r}$ wherein r ranges from about 0.9 to less than 1, a solid solution $(Ta_2O_5)_{s}$ - $(Al_2O_3)_{1-s}$ wherein s ranges from 0.9 to less than 1, a solid solution of $(Ta_2O_5)_{t-}(ZrO_2)_{1-t}$ wherein t ranges from about 0.9 to less 1, a solid solution of $(Ta_2O_5)_{u-}(HfO_2)_{t-u}$ wherein u ranges from about 0.9 to less than 1. However, applicant does not disclose that these materials will provide unique or different results, when used in a device, from the Ta_2O_5 material, listed in the group, disclosed by Wu. Therefore the other materials that are not shown by the prior arts of

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record are considered to be equivalent and obvious substitutes for the Ta_2O_5 disclosed in the prior art of record. Additionally no criticality has been placed on using one material over the other and therefore the substitution of one of the other claimed materials for the high dielectric layer does not provide patentable distinction from the material given in the prior arts of record.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ron E. Pompey whose telephone number is (571) 272-1680. The examiner can normally be reached on compressed 8:00 – 17:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael S. Lebentritt can be reached on (571) 272-1873. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Ron Pompey

January 10, 2005

MICHAEL LEBENTRITT
SUPERVISORY PATENT EXAMINER